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Attorney Docket Number MLSF 1060-1

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			II C DATEN	T DOCUMENTS	
Examiner initials*	Cite No.1	Document Number Number-Kind Code ² (************************************	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, When Relevant Passages or Relevan Figures Appear
	A1	^{US-} 4,822,975	04-18-1989	Torigoe	
	A2	^{US-} 4,970,546	11-13-1990	Suzuki et al.	
	A3	^{US-} 4,879,605	11-07-1989	Warkentin et al.	
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FOREIGN PATENT DOCUMENTS							
Examiner Cite Initials* No.		Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	П	
		Country Code ³ "Number ⁴ "Kind Code ⁵ (# known)	MM-DD-YYYY	7 pprisant or oron position	Or Relevant Figures Appear	T°	
	B1	JP 02135723 A2	05-24-1990	Nikon Corp.	Abstract only		
	B2	JP 03179357 A2	08-05-1991	Nikon Corp.	Abstract only		
	B3	WO 0193303 A2	12-06-2001	Chabala et al.			
	B4	WO 03079111 A1	09-25-2003	Tyrell et al.		П	
	B5	EP 1324137 A2	07-02-2003	ASML Netherlands B.V.			

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			CLOSURE	Filing Date	30 March 2007	
STATEMENT BY APPLICANT			PPLICANT	First Named Inventor	Torbjorn Sandstrom	
	(Use as many she	ets as n	acassary)	Art Unit	1756	
,,				Examiner Name	Unassigned	
Sheet	2	of	2	Attorney Docket Number	MLSE 1060-1	

		NON PATENT LITERATURE DOCUMENTS		
Examiner Initials*	Cite No.1			
	C1	PCT International Search Report and Written Opinion of the International Searching Authority for International Application No. PCT/SE2004/001701 (filed 19 November 2004), mailed 11 March 2005.		
	C2	PCT International Search Report for International Application No. PCT/SE2004/001700 (filed 19 November 2004), mailed 02 May 2005.		
	СЗ	MCCARTHY, A. M. et al. "A Novel Technique for Detecting Lithographic Defects," IEEE Transactions on Semiconductor Manufacturing, Vol.1, No. 1 p.10-15 (Feb. 1998).		
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	C5	Rieger, M. L. et al. "Lithographic Alternatives to PSM Repair," Proceedings of SPIE, Vol. 1674, Optical/Laser Microlithography V, p.609-617 (1992).		
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	C8	WOLF, S. "Advanced Lithography," p.493-513 in Silicon Processing for the VLSI Era, Vol.1 - Process Technology, Lattice Press, Inc. (1986).		

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